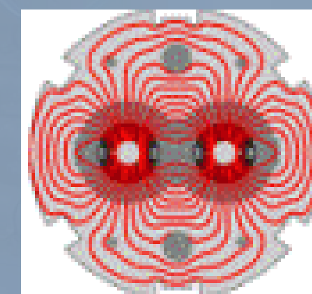
Lessons Learnt from Beam Commissioning and Early Beam Operation of the Beam Loss Monitors (incl. outlook to 5 TeV)



Preconditions for operating at 5 TeV in 2010

Session 1 - 25th January 2010

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for the BLM team

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Outline

- Introduction
- Operational Experience
  - Noise and Offset
  - Dependability (Reliability, Availability and Safety)
  - Accuracy of Thresholds
  - Known Limitations
- Threshold Levels Compared to Dynamic Range
- Extrapolation to Higher Intensities
  - Beam Cleaning
  - Injection Losses
- Summary

Introduction

Introduction

- Up to now very satisfying performance
- Machine protection functionalities are being **phased in**, in order not to compromise the availability during commissioning
  - Beam loss thresholds: from masked to unmasked in stages (end of 2009: running with most channels unmasked)
  - Acquisition system self tests – failure aborts beam – operational during 2009 run (see talk Ch. Zamantzas Evian 2010)
  - Sequencer driven regular system tests – failure or non-execution within 24 hours inhibits beam injection – to become operational before 2010 run

Introduction

- The important step for the BLM system is to go to unsafe beams (10^{12} p at 450 GeV, see Jörg's talk). This will happen in 2010!
- → to reach full protection level we need (mostly not covered in this talk):
  - Technological tasks (see talk Ch. Zamantzas Evian 2010)
  - Validate threshold settings (document for MPP approval in preparation)
  - MPS tests (EDMS 896394)
  - Apply all procedures for changes (EDMS 1027851)

Operational Experience

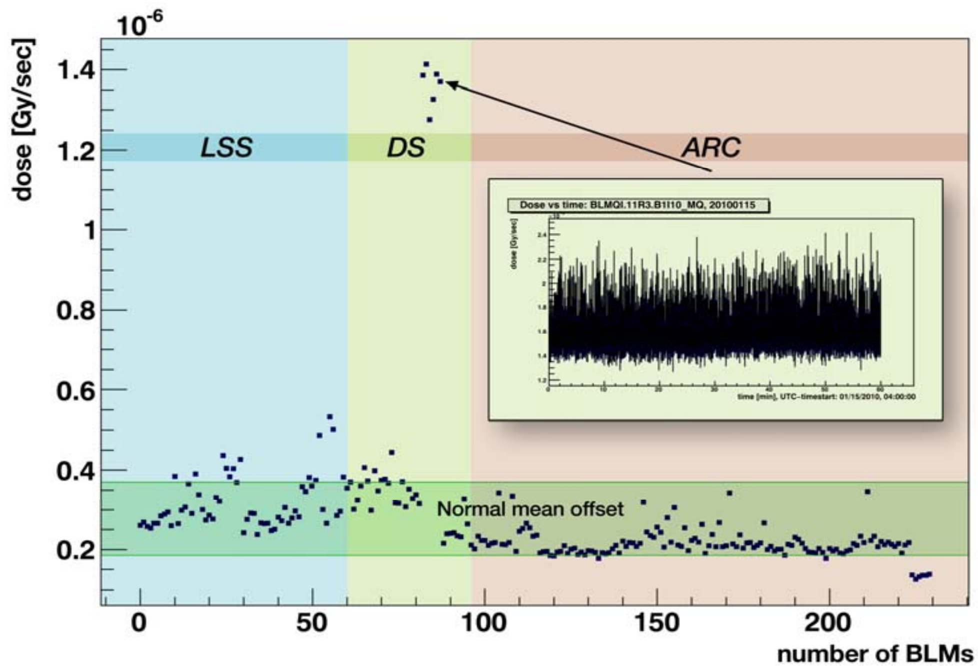
- Noise and Offset
- Dependability (Reliability, Availability and Safety)
- Accuracy of Threshold
- Known Limitations

Noise and Offset

- Important for availability (false dumps)
- Onset of problem detected early by about daily checks on offset and noise for each channel, cause can be identified (cable noise, card problem, ...)
- Cables had been exchanged (up to 800 m), noise reduction: **factor 2**
- Next shut-down: install single pair shielded cables, noise reduction: > **factor 5**
- Development of kGy radiation hard ASIC readout (PhD Giuseppe Venturini, ≈4 years): avoid long cables

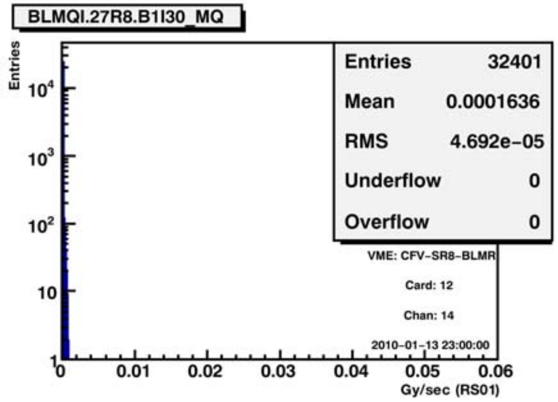
Example mean offset level right of IP3

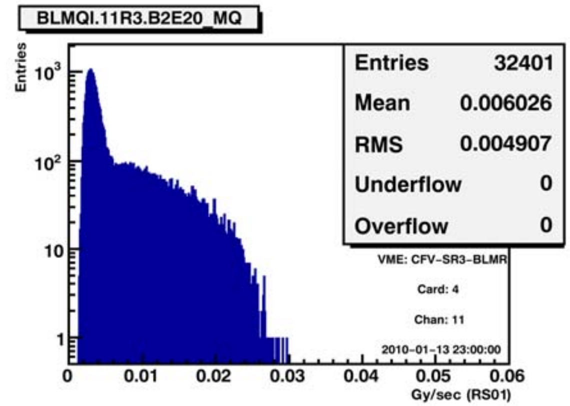
- Some bad channels in the DS have been repaired
- Long cables in LSS and DS lead to higher fluctuations



Noise and Offset

Noise single channel frequency distribution over 9 hours, low noise - short cable (left), high noise - long cable (right)

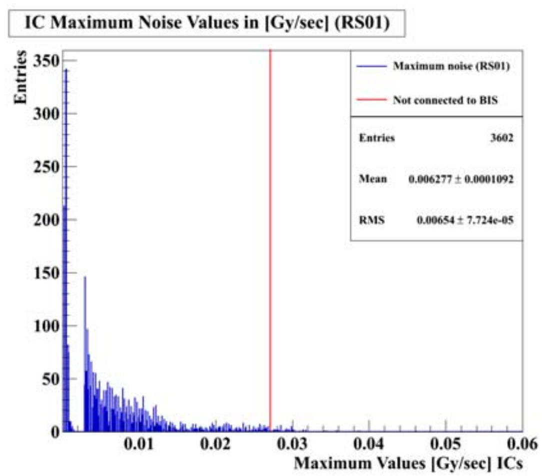


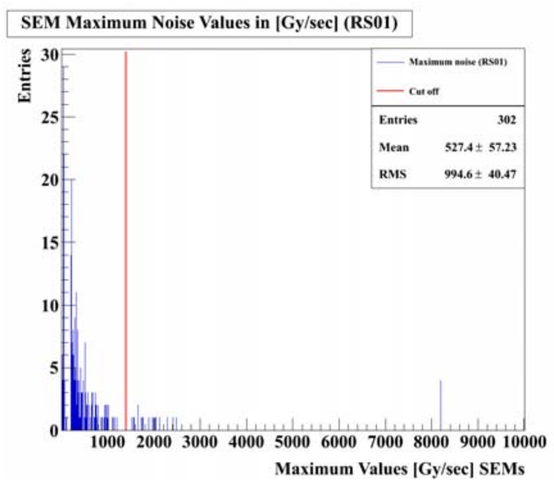


Max. noise frequency distribution, Ionization Chambers (IC) - left, Secondary Emission Monitors (SEM) - right

SEMs have a higher percentage of high noise

Max. noise above red line → channel will be repaired





≈3600 IC

≈300 SEM

A SEM is always installed next to an IC, it is less sensitive by factor of 70.000

Dependability

- Safety
  - No safety related issues detected (hardware, firmware, software, parameters).
- Availability, too early to give hardware failure and intervention rate. All hardware problems had been detected before the run. About one month of running: no newly developed problems.
  - 3 hardware problems giving false dumps
    - 2 previously detected, but not considered urgent (optical fiber, tunnel card)
    - 1 detected intermittently during the summer (mezzanine surface card)

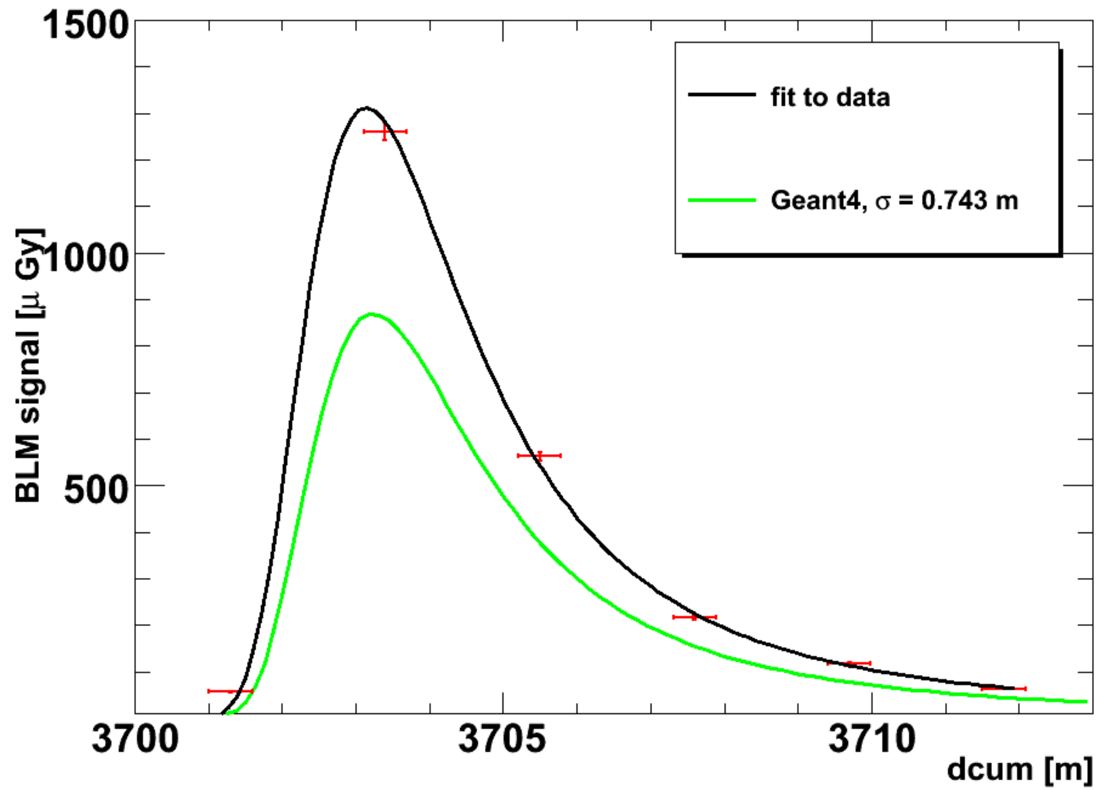
Accuracy of Thresholds

- All quenches so far on MB (all injected beam). Most likely loss with circulation beam locations are the quadrupoles.
- 2 quenches in 2008 (injected beams): signals in BLMs could be reproduced by GEANT4 simulations to a factor of 1.5

  → thresholds raised by ≈50%

Analysis of second quench

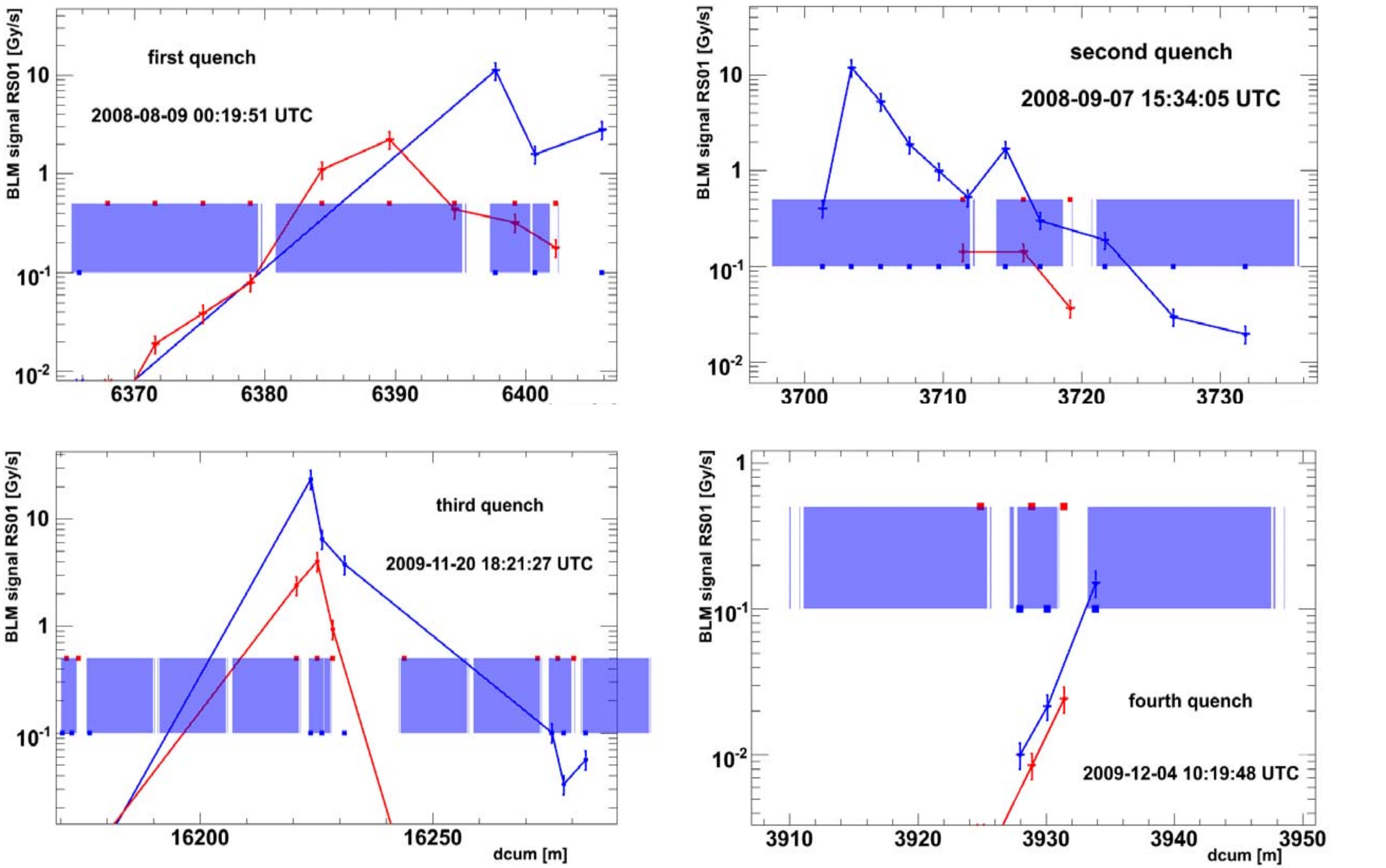
LHC Project Note 422



The Four Quenches

analyzed (opposite beam equipped)

analyzed



highest IC saturation

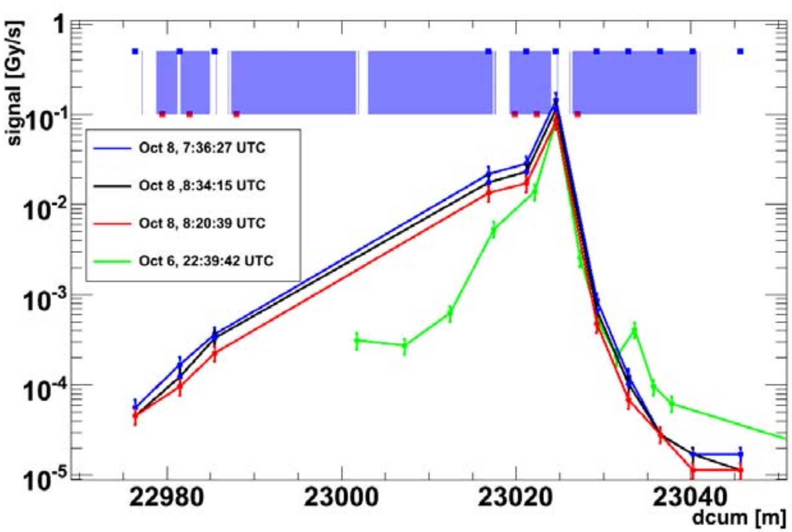
MB not equipped

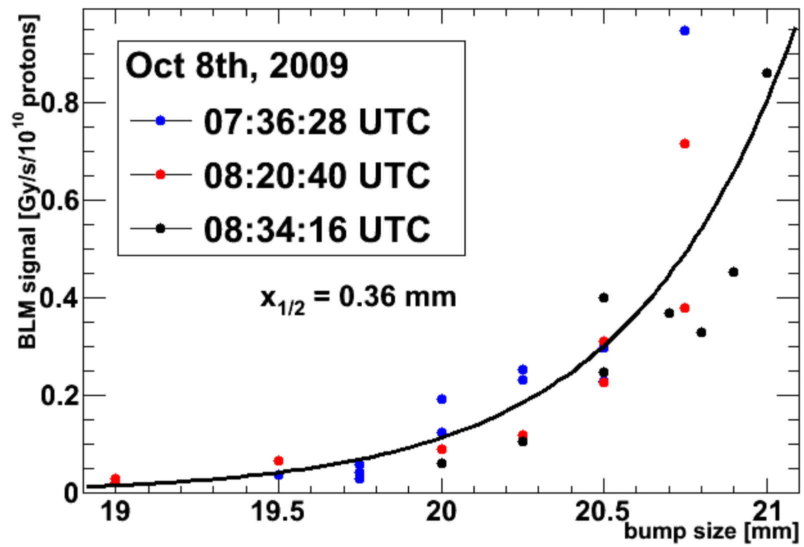
Accuracy of Thresholds

- → beam tests: provoke either a quench, or better, a 'recovering quench' on different magnets.
  - Injected beam – detect with special version of nQPS
  - Steady state (circulation beams) – detect with magnet temperature monitors
  - Propose these tests for very beginning of 2010 run

Safety of 'Recovering Quench' Test

- Similar to 2009 beam dump test with reduced threshold levels and beam bump.
- nQPS Voltage difference detection level to be set at 50 mV (factor 4 below the QPS and factor 2 below nQPS limit).
- Conditions of the bump are well understood and very reproducible – nQPS test will (most likely) not cause a magnet quench and should be perfectly safe for the machine.



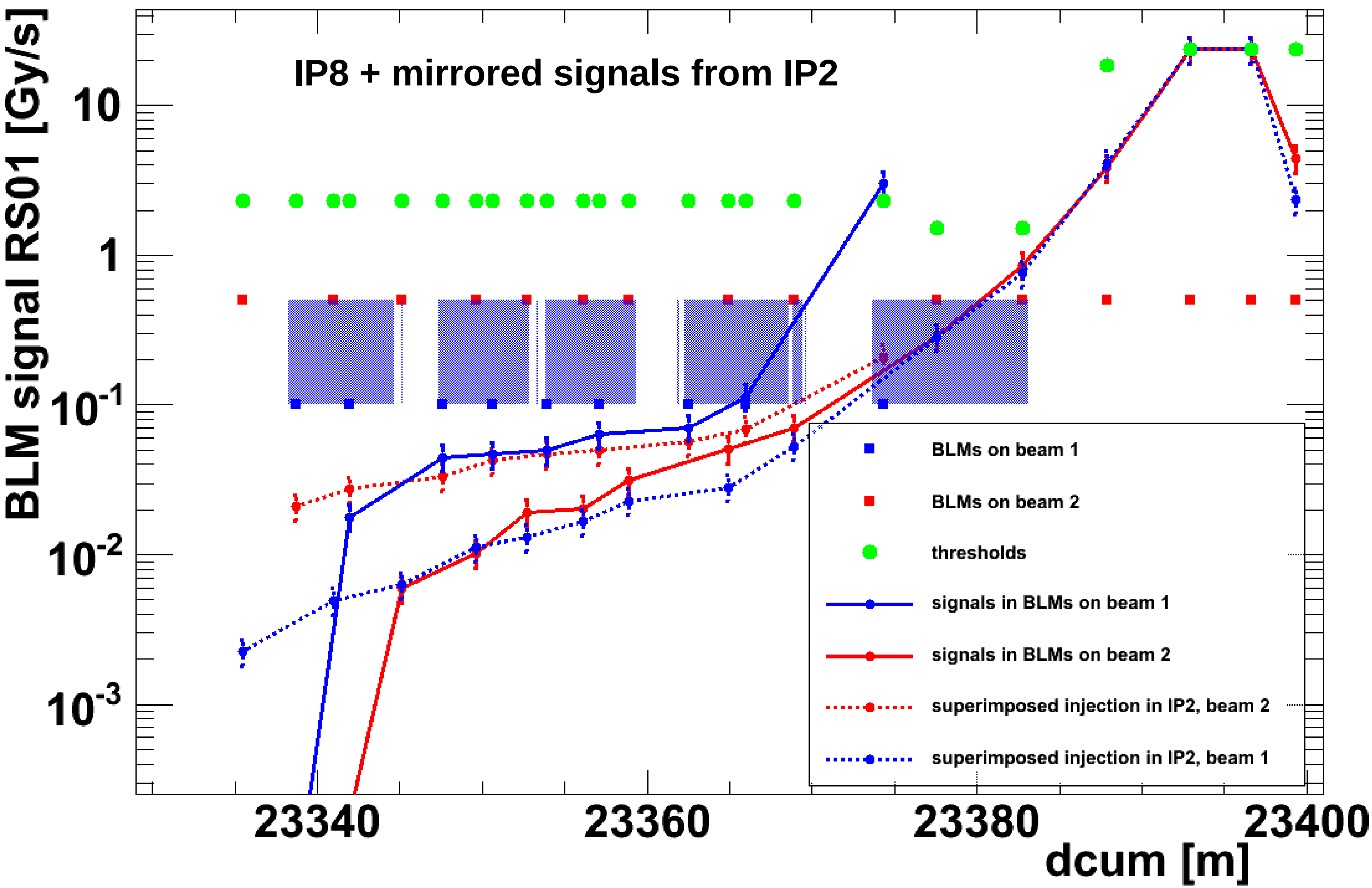


Position and detection reproducibility of 4 beam tests

Known Limitations

- **TDI at over-injection:** IC signal short integration times over electronic measurement limit – installation of capacitor
- **Triplet magnets at over-injection:** BLM over threshold. Measurements and beam tests suggest that radiation from TDI reaches monitors at triplet magnets from the outside (through the tunnel)
  - Long term solution: shielding
  - Short term solution: increasing the short integration time threshold or the monitor factor or installing an additional capacitor.

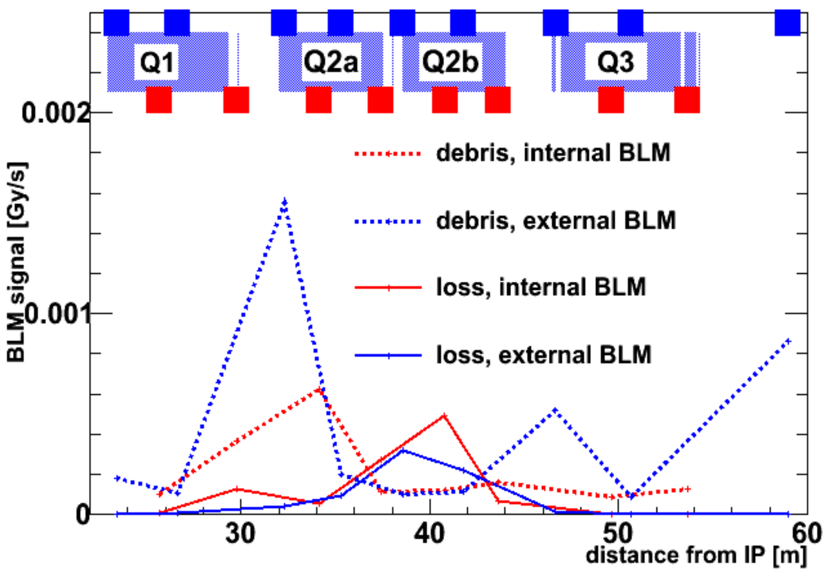
Triplet at Over-Injection



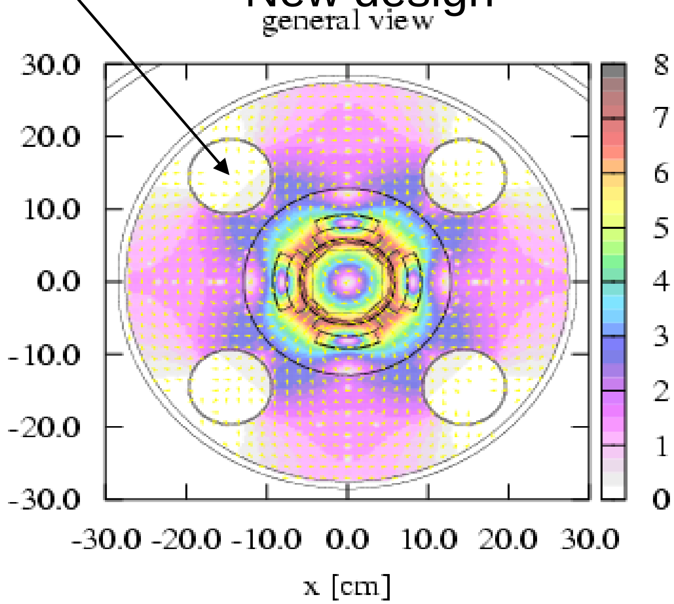
Known Limitations

- **Triplet magnets at collision:** debris from interaction same magnitude signal as a critical loss
  - Long term solution: new monitors placed close to the coil of new triplet. *BLMs on Triplets preliminary studies*, Mariusz Sapinski et al., IR upgrade WG meeting 2009.02.12, EDMS 1049072
  - Short term: no problem up to luminosity of 10^{33} cm^{-2} s^{-1}

Current set-up



New design



Losses at Injection

W. Bartmann Evian 2010

- TCDI set up:
  - losses in the ring already close to BLM interlock limit for pilot bunch...scraping in the SPS
  - Ratio of one pilot bunch to one nominal SPS batch: 6.4e3

TCDIs at..	BLM: threshold/losses B1/B2		
	5e9 (B1/B2)	**1.6e10**	**Nominal**
4.5 σ hor/vert	10/20		*$1\cdot10^{-3}/2\cdot10^{-3}$*
6.0 σ hor / 4.5 σ vert	30/60		*$3\cdot10^{-3}/6\cdot10^{-3}$*
6.0 σ hor / 4.5 σ vert + SPS scraping		$10^{3}/10^{5}$	*$10^{-1}/10$*

→ Superconducting machine demands a very clean injection

- ❑ Scrape tails in SPS
- ❑ Improve beam 1 to the quality of beam 2
- ❑ **Unfortunately we did not reproduce the above results → last chapter of this talk**

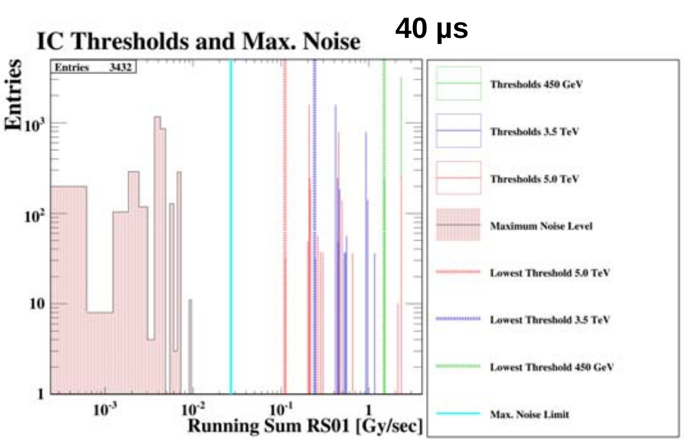
Known Limitations – Dynamic Range

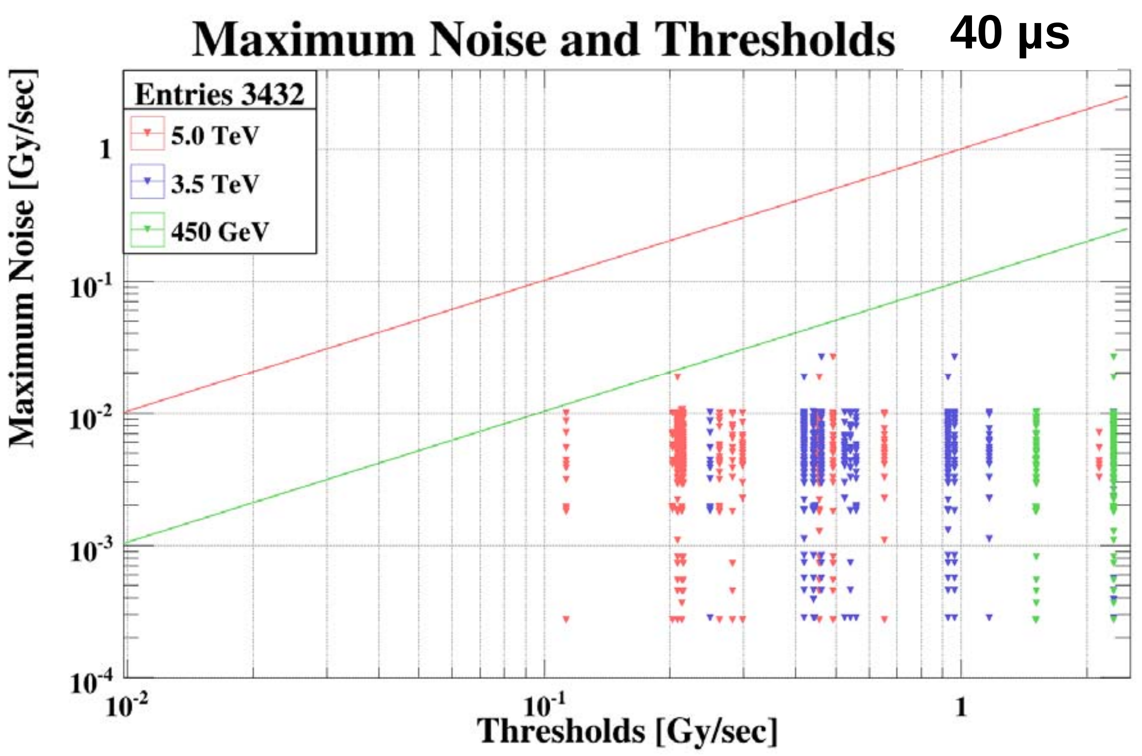
- SEM noise
  - Spurious signal: insulation problem - being corrected now
  - High noise (≈2000 Gy/s for short integration time)
    - Ambiguity for short losses in the gap between IC and SEM dynamic range
    - Thresholds cannot be set in SEM
- Partial activation of beam abort functionality was not foreseen in electronics (thresholds partially in SEM and partially in IC)
  - Installation of additional capacitors to spread the signal over longer time
  - Depending on requirement: new monitor type, small IC, 30 times less sensitive than IC (installation during 2010), ≈56 monitors.

Threshold Levels Compared to Dynamic Range

- Are the thresholds at higher energies still safely above the noise levels? → yes (analyzed IC 40 µs, 1.3 s and 84 s integration time window up to now)

Data set of 10 days: 18.12.2009 - 25.12.2009 and 08.01.2010 - 15.01.2010

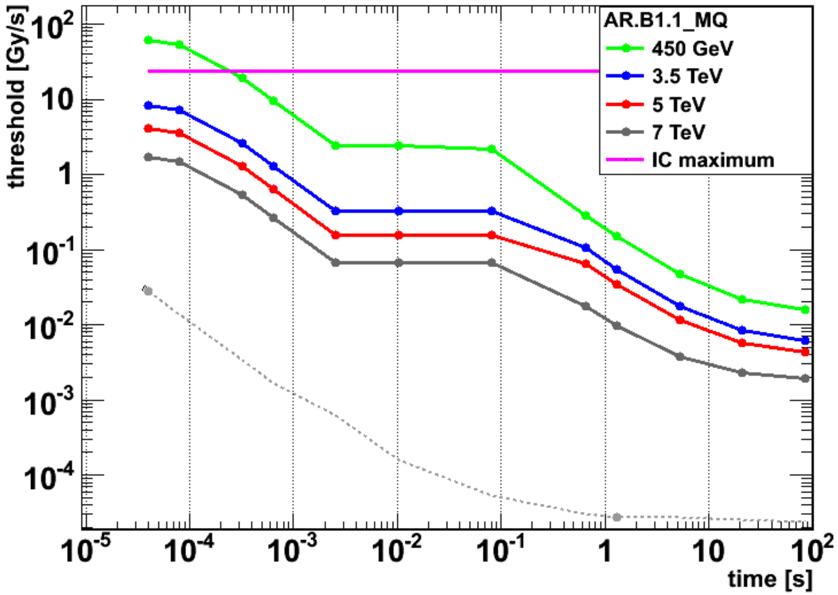


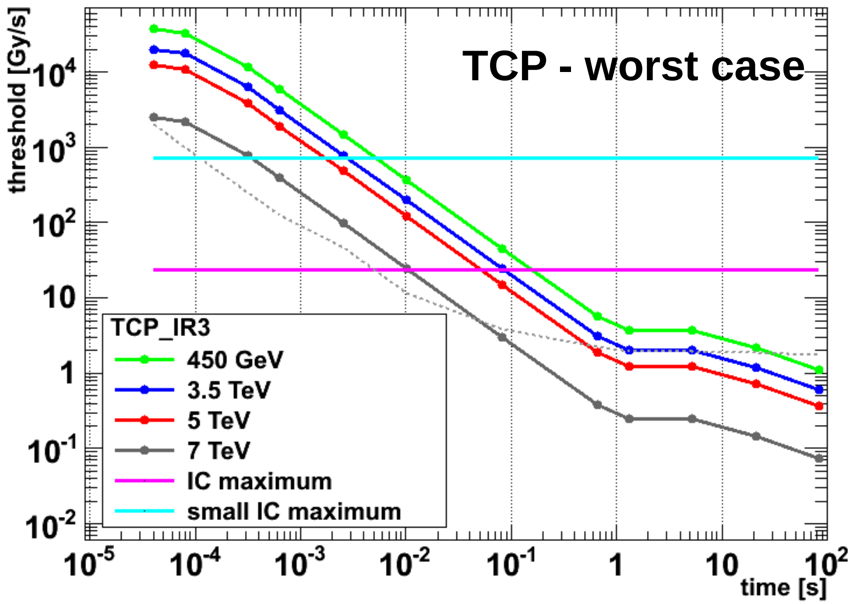


Threshold levels compared to dynamic range

- Problem reduces with higher energies
- TCP: worst case
  TCSG and TCLI: 10 times lower thresholds
  → capacitor (up to factor 100)
- Similar for warm magnets
  → most locations should need no changes
- possible limitation? → see next slides

Highest threshold cold magnets: OK (as defined in functional spec)





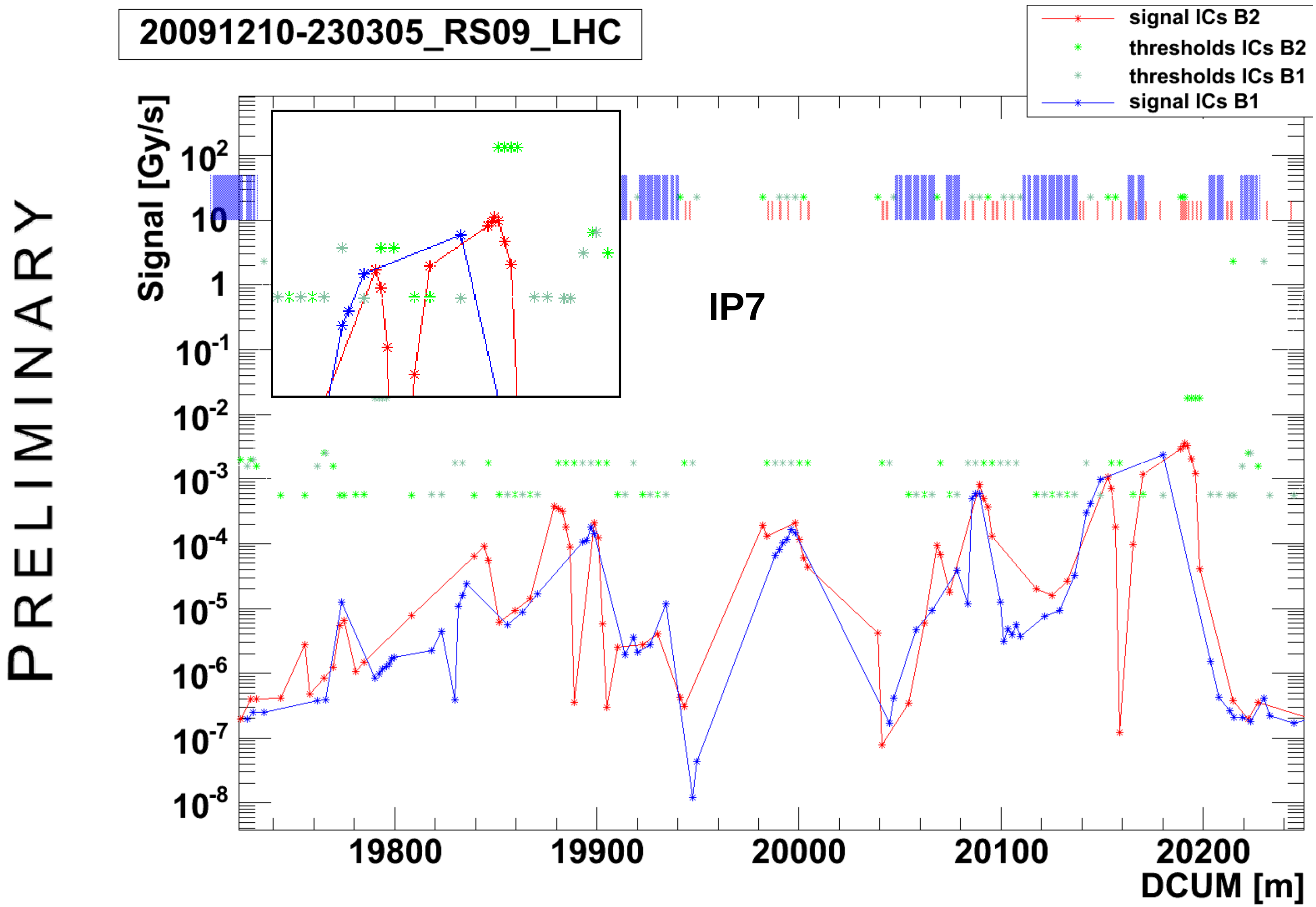
Extrapolation to Higher Intensities

- Beam Cleaning
- Injection Losses

Extrapolation to Higher Intensities

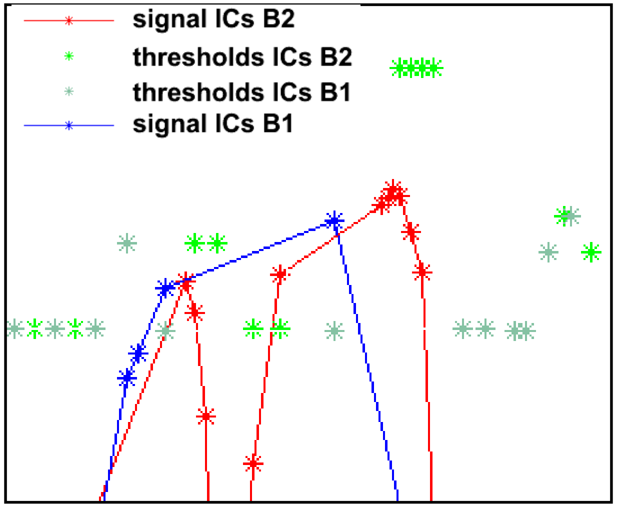
- Preliminary results
- Assuming intensity increases, all other conditions unchanged
- 6 data sets analyzed (same data sets as presented in Evian by Ch. Bracco and W. Bartmann)
- At what intensity do we reach the loss threshold? Which are the most-critical elements?
- Collimation cleaning 450 GeV (1.3 s loss data compared to 84 s thresholds), scaled to nominal intensity
  - B1 and B1 longitudinal cleaning
  - B1 vertical and B2 horizontal cleaning
- Injection (40 µs loss data compared to 40 µs thresholds)
  - B1 and B2, cleanest injections: SPS scraping, TCDI 6 σ hor. / 4.5 σ vert.

Cleaning - Beam 2 Horizontal



Cleaning - Transversal

Most-Critical Elements at nominal intensity 3E14	*Beam lifetime at threshold [minutes]*
Beam 2 horizontal cleaning	
BLMEI.06R7.B1E10_TCLA.B6R7.B1	62 – 86
BLMEI.06R7.B1E10_TCLA.A6R7.B1	26 – 37
BLMQI.04L6.B2I10_MQY	18 – 24
Beam 1 vertical cleaning	
BLMEI.05R7.B2I10_TCSG.B5R7.B2	1 – 1.5



Beam 2 horizontal:

- TCLA losses seem to be caused by “crosstalk” particle showers from B2
- Most critical cold element in IP6
- No limits from BLM dynamic range (all long integration time thresholds are within the dynamic range of the BLM system)

PRELIMINARY

Cleaning - Longitudinal

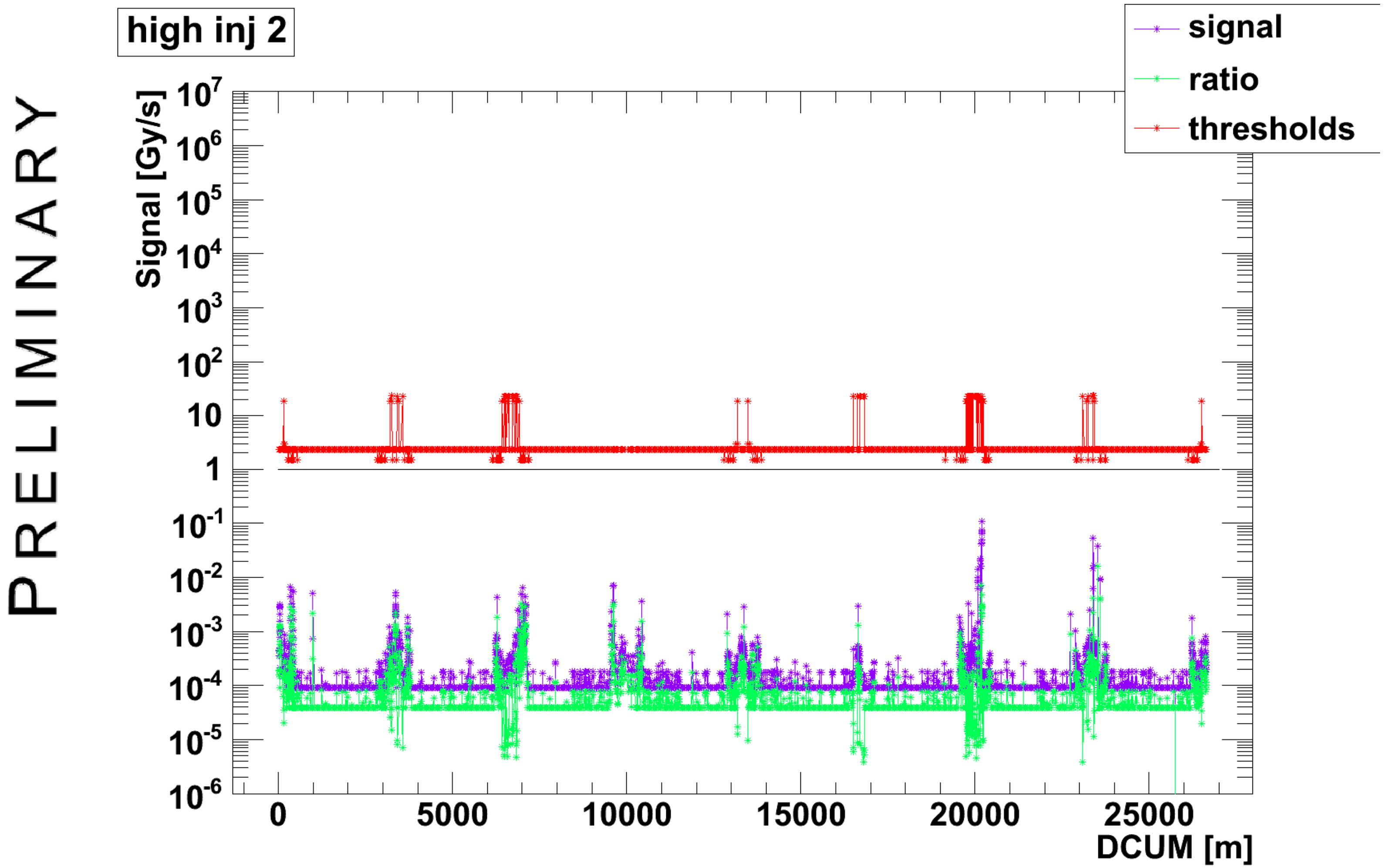
Most-Critical Elements at nominal intensity 3E14	*Beam lifetime at threshold [minutes]*
Beam 1 longitudinal cleaning	
BLMEI.05L3.B1I10_TCSG.5L3.B1	13 – 18
BLMEI.05R3.B1I10_TCLA.A5R3.B1	7 – 10
BLMEI.08R3.B1I23_MBB	7 – 10
Beam 2 longitudinal cleaning	
BLMEI.08R3.B2I30_MBA	22 – 31
BLMEI.05R3.B2E10_TCSG.5R3.B2	7 – 10
BLMEI.05L3.B2E10_TCLA.A5L3.B2	5 – 7

- B2: most critical element is a cold dipole
- Losses localized: most-critical elements in IP3
- Most-critical TCSG and TCLA correspond for B1 and B2, MBs are next to each other
- No limits from BLM dynamic range (all long integration time thresholds are within the dynamic range of the BLM system)

PRELIMINARY

Injection with SPS scraping

- SPS scraping, TCDI 6 σ hor. / 4.5 σ vert., Beam 2, 2e10 p



Injection with SPS scraping

Most critical	*Beam 1*	*Number of injected protons at threshold*
16% of 38 most critical elements are cold magnets		
Collimator	BLMEI.06L7.B1E10_TCP.A6L7.B1	1.5E+11
Warm magnet	BLMEI.06L7.B1E10_MBW.B6L7	5.5E+11
Cold magnet	BLMQI.08L2.B1E30_MQML	6.7E+11
	Beam 2	
50% of 30 most critical elements are cold magnets		
Collimator	BLMEI.06R7.B2I10_TCP.C6R7.B2	3.4E+12
Cold magnet	BLMEI.04R8.B2E10_MBXB	3.9E+12
Warm magnet	BLMEI.06R8.B2E10_MSIB	9.8E+12

nominal: 3E13
2010: 4E12

PRELIMINARY

- Numerous elements (collimators, cold and warm magnets) yield similar limits for injected protons
- IC thresholds in warm elements limited by BLM dynamic range. But, losses at cold magnets about equally close to threshold (≈3 times below quench limit).
- → injection losses need to be reduced further, scraping in the SPS seems crucial
- → possible to increase thresholds on primary and secondary collimators and warm magnets (additional capacitors, small IC) but not on cold elements

Summary

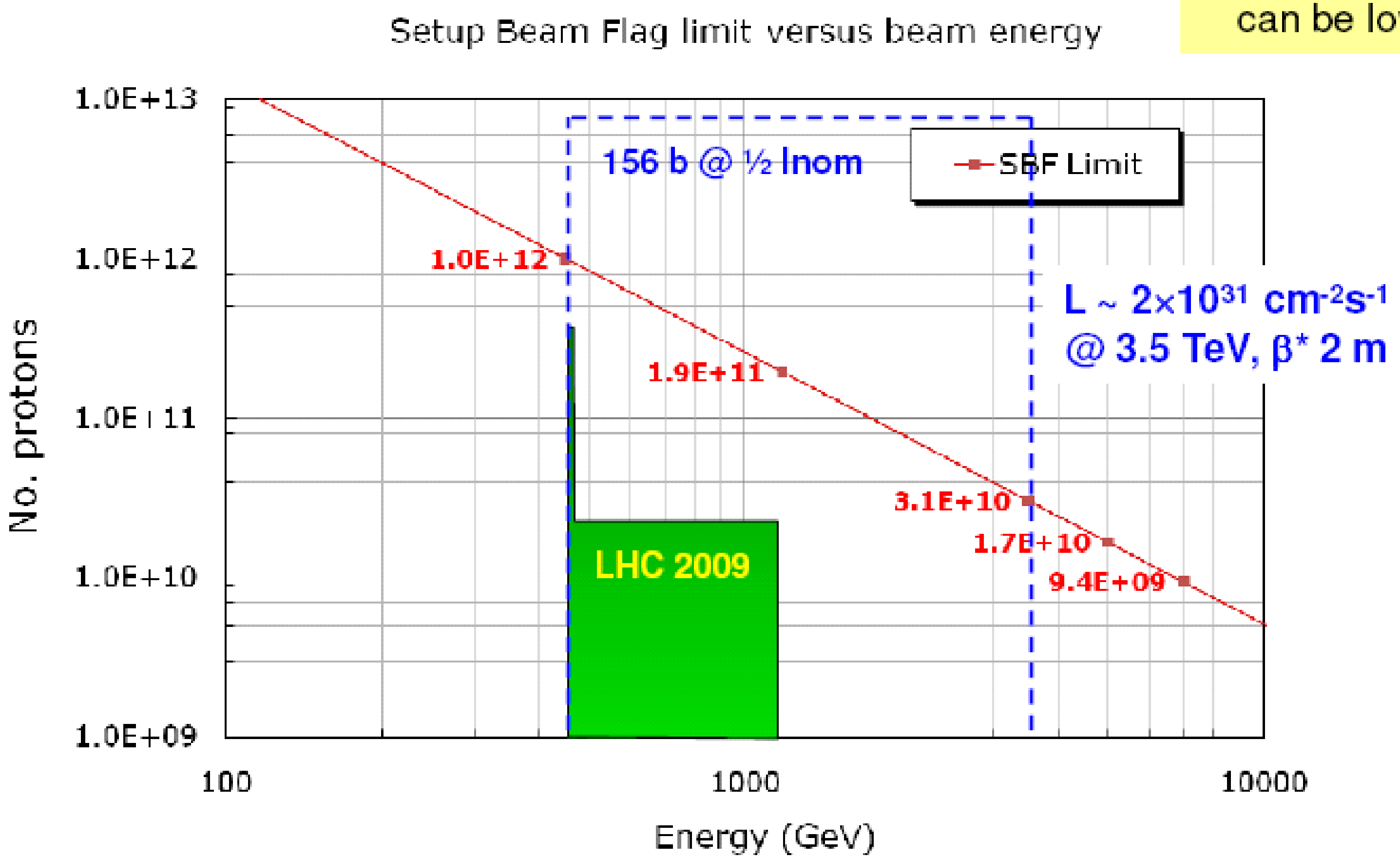
- Crucial to reach full protection level
  - Beam test to determine safe setting of threshold levels, full application of procedures
- Known BLM system limitations and upgrades look compatible with LHC schedule
  - Typically, warm elements should have higher thresholds
  - Certain locations **need** higher thresholds (add capacitor or install new small IC, choose different monitor location, install shielding, etc.)
- No additional limitation found for energies up to 5 TeV
- Collimation cleaning looks very promising
- Injection losses have to be substantially reduced (even for 2010)
  - Various cold magnets are affected
  - BLM system seems not to be the limiting factor

PRELIMINARY

Some more slides

MP Footprint

For TCTs the limit can be lower !!



A pilot bunch is the only beam that can be used for commissioning (and for most MD) activities at ≥ 3.5 TeV !

Noise and Offset

Range [bits]	~ Range [Gy/s] 40µs	monitors in %	Nr. of monitors	
1-30	0 - 0.003	20.1	690	very good
30-100	0.003 - 0.01	71.2	2445	good
100-200	0.01 - 0.02	7.7	264	ok
200-300	0.02 - 0.03	0.7	23	candidates for problematic channels
> 300	> 0.03	0.0	0	critical noise
= 0	no data	0.3	10	no data

SEM Noise (302 monitors) 18.12 .2009-25.12.2009 RS01

Range [bits]	Range[Gy/s] 40µs	Monitors in %	Nr. of monitors
0.0-30.0	0.0-190.0	2.65	8
30.0-100.0	190.0-633.0	15.89	48
100.0-200.0	633.0-1265.0	52.32	158
200.0-300.0	1265.0-1898.0	12.25	37
>300.0	>1898.0	16.56	50
0	No data	0.3	1

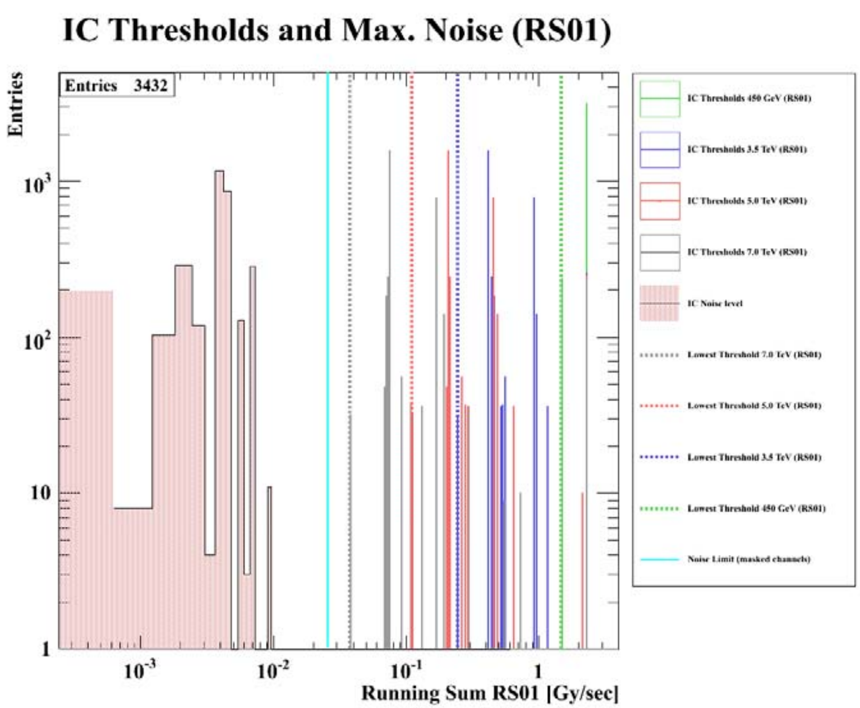
IC Offset (3592 monitors) 18.12.2009 (1hour) RS09

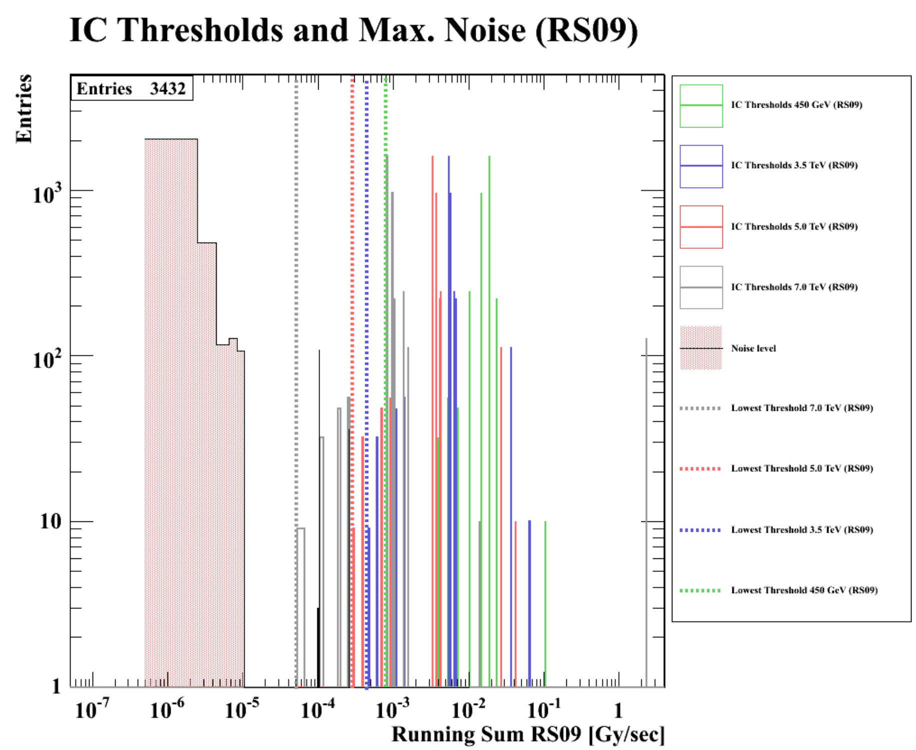
Range [bits/1310.72ms]	Range [Gy/s x10^{-7}] in 1310.72ms	Monitors in %	Nr. of monitors	Comment
6.0-53.0	0.19 -1.85	6.91	249	Too low
53.0-134.0	1.85-3.7	77.71	2799	Very good
134.0-201.0	3.7-5.56	6.83	246	good
201.0-537.0	5.56-14.8	3.28	118	Reset needed
537.0-1340.0	14.8-37.0	5	180	problematic
>1340.0	>37.0	0	0	serious card problem

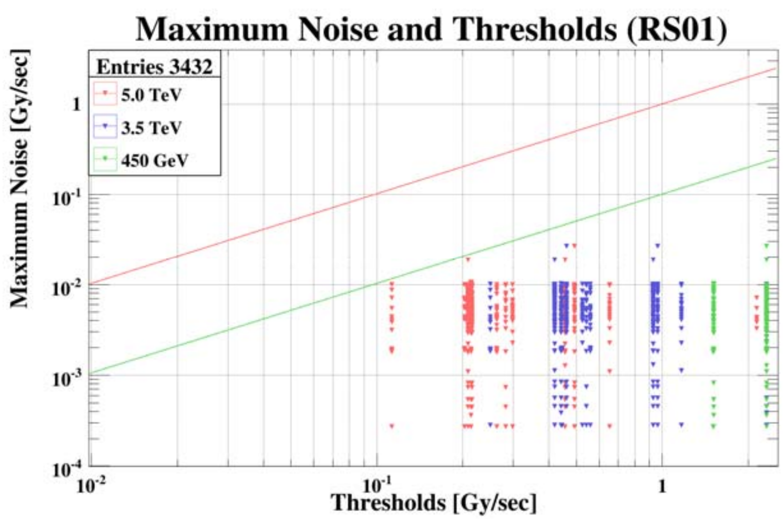
SEM Offset (302 monitors) 18.12.2009 (1hour) RS09

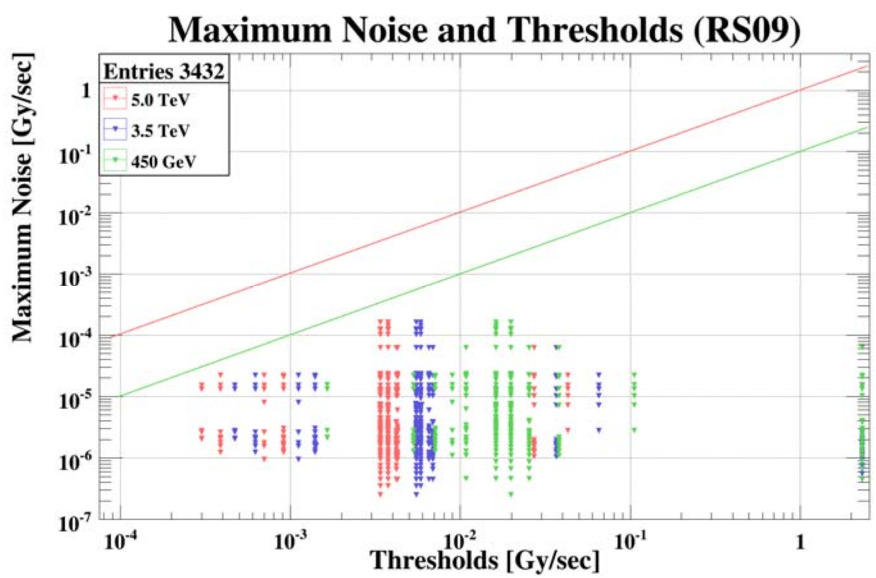
Range [bits/1310.72ms]	Range [Gy/s] in 1310.72ms	Monitors in %	Nr. of monitors	Comment
10.0-104.0	0-0.02	2	6	Too low
104.0-208.0	0.02-0.04	88	266	Very good
208.0-312.0	0.04-0.06	7.8	24	good
312.0-832.0	0.06-0.16	0	0	Reset needed
832.0-2080.0	0.16-0.4	1.1	3	problematic
>2080.0	>0.4	1.1	3	serious card problem

- Factor between noise level and lowest threshold:
- RS01: 450GeV: ≈150 3.5TeV: ≈25 5.0TeV: ≈11
- RS09: 450GeV: ≈81 3.5TeV: ≈37 5.0TeV: ≈20






Maximum Noise and Thresholds (RS01)
Entries 3432
5.0 TeV
3.5 TeV
450 GeV
Maximum Noise [Gy/sec]
Thresholds [Gy/sec]


Maximum Noise and Thresholds (RS09)
Entries 3432
5.0 TeV
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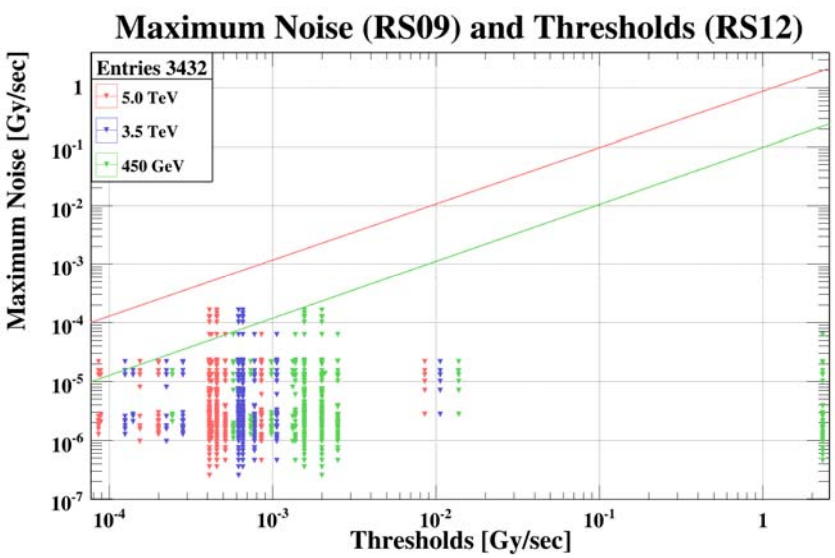
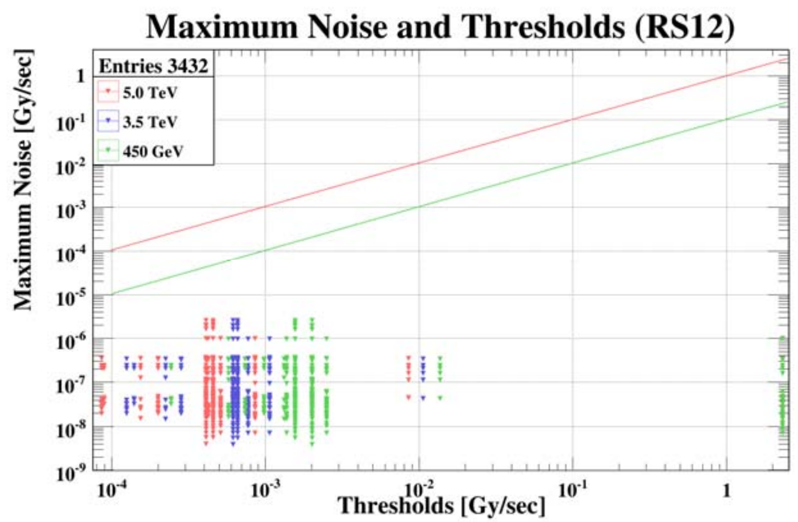
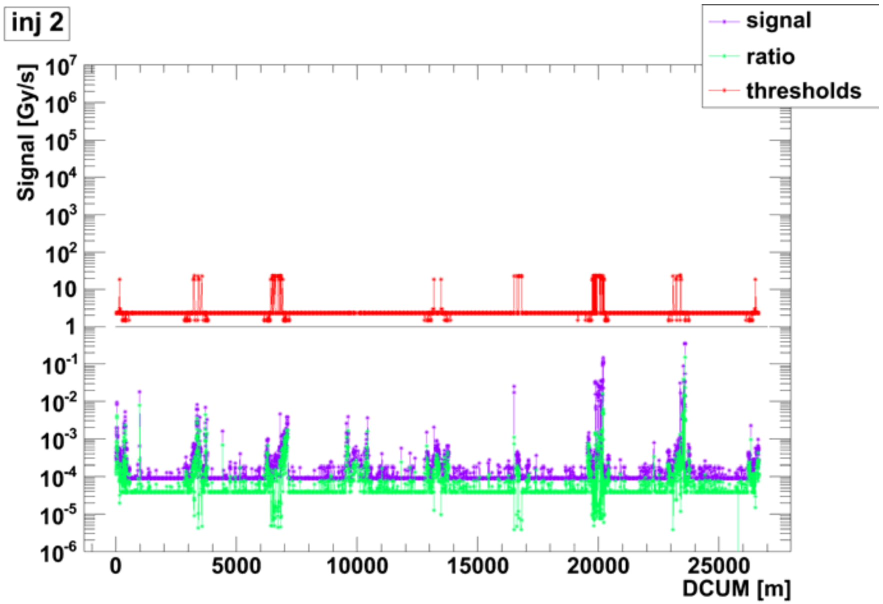
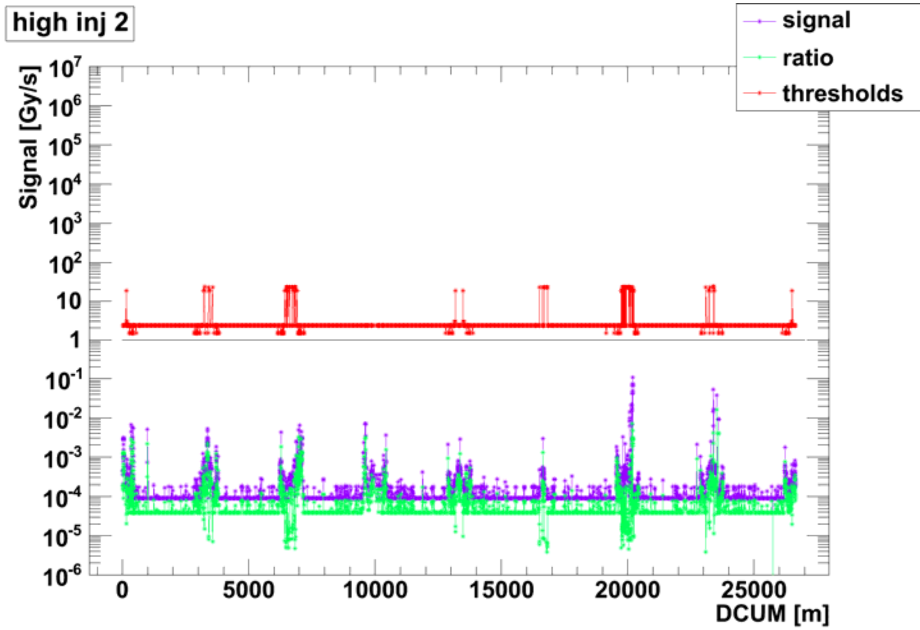
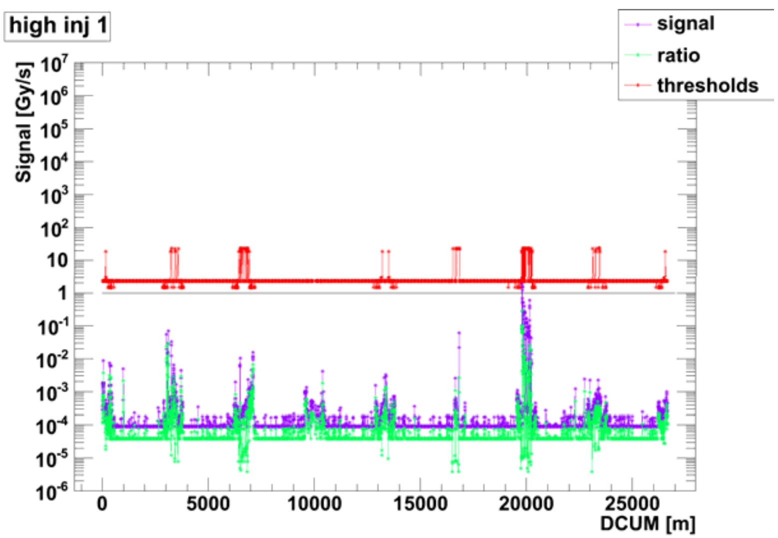
Thresholds [Gy/sec]


Maximum Noise (RS09) and Thresholds (RS12)
Entries 3432
5.0 TeV
3.5 TeV
450 GeV
Maximum Noise [Gy/sec]
Thresholds [Gy/sec]

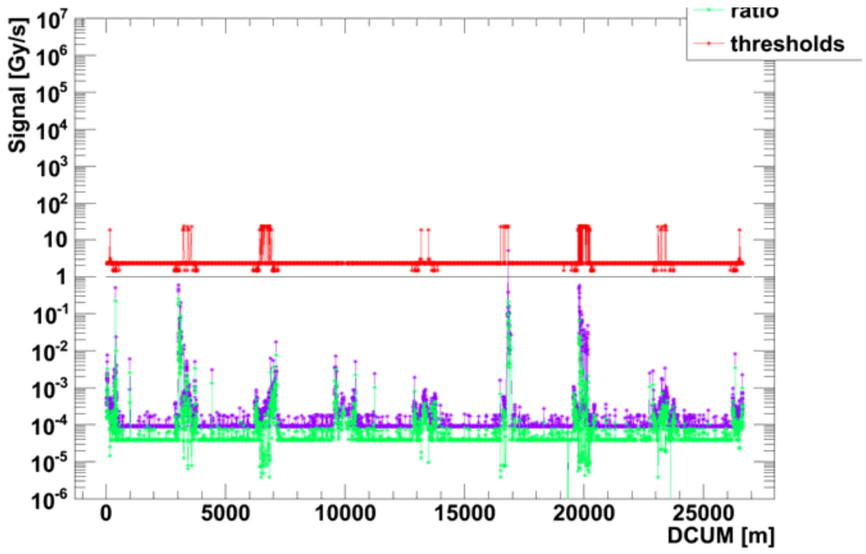

Maximum Noise and Thresholds (RS12)
Entries 3432
5.0 TeV
3.5 TeV
450 GeV
Maximum Noise [Gy/sec]
Thresholds [Gy/sec]







PRELIMINARY



- Beam 2 longitudinal (right)
- Beam 1 longitudinal (bottom right)
- Beam 2 horizontal (bottom left)